

Abstract

The present invention relates to a measurement arrangement for detecting ageing processes in individual light-emitting diodes which makes it possible to identify, and subsequently to compensate, a loss of brightness in light-emitting diodes. In this context, a relative measurement of brightness intensity is taken. The present invention further relates to a correspondingly set-up method for detecting ageing processes in individual light-emitting diodes and to a computer program product comprising control commands which implement the method.